



CTL0343NS-R3

N-Channel Enhancement MOSFET

Features

- Drain-Source Breakdown Voltage $V_{DS} - 20\text{ V}$
- Drain-Source On-Resistance
 $R_{DS(ON)} 58\text{m}\Omega$, at $V_{GS} = 10\text{V}$, $I_D = 3.4\text{A}$
 $R_{DS(ON)} 66\text{m}\Omega$, at $V_{GS} = 4.5\text{V}$, $I_D = 2.7\text{A}$
 $R_{DS(ON)} 88\text{m}\Omega$, at $V_{GS} = 2.5\text{V}$, $I_D = 1.0\text{A}$
- Continuous Drain Current at $T_C = 25^\circ\text{C}$ $I_D = -3.1\text{A}$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

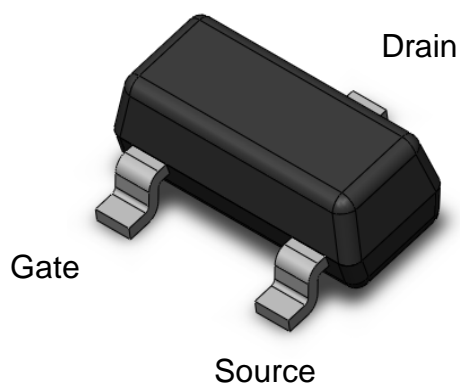
Applications

- Power Management
- Lithium Ion Battery

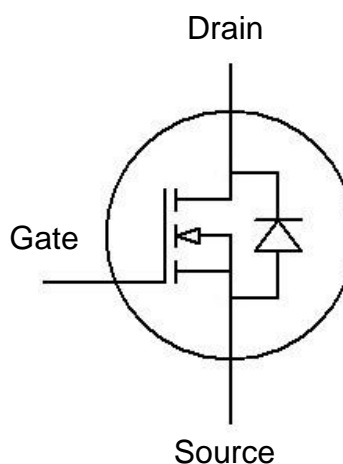
Description

The CTL0343NS-R3 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits where low in-line power loss are needed in a very small outline surface mount package.

Package Outline



Schematic





CTL0343NS-R3

N-Channel Enhancement MOSFET

Absolute Maximum Rating at 25°C

Symbol	Parameters	Test Conditions	Min	Notes
V _{DS}	Drain-Source Voltage	30	V	
V _{GS}	Gate-Source Voltage	±12	V	
I _D	Continuous Drain Current	2.9	A	1
I _{DM}	Pulsed Drain Current	12	A	1
P _D	Total Power Dissipation	1.0	W	2
T _{STG}	Storage Temperature Range	-55 to 150	°C	
T _J	Operating Junction Temperature Range	-55 to 150	°C	

Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R _{θJA4}	Thermal Resistance Junction-Ambient (t=10s)		--	125	--	°C /W	1,4



N-Channel Enhancement MOSFET

Electrical Characteristics $T_A = 25^\circ\text{C}$ (unless otherwise specified)

Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
B_{VDSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = -250\mu A$	30	-	-	V	
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = 30V, V_{GS} = 0V$	-	-	1	μA	
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 12V, V_{DS} = 0V$	-	-	± 100	nA	

On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS} = 10V, I_D = 3.4A$	-	58	75	m Ω	3
		$V_{GS} = 4.5V, I_D = 2.7A$	-	66	85	m Ω	
		$V_{GS} = 2.5V, I_D = 1.0A$	-	88	120	m Ω	
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = -250\mu A$	0.6	1.0	1.4	V	3

Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C_{ISS}	Input Capacitance	$V_{GS} = 0V,$ $V_{DS} = 10V$ $f = 1MHz$	-	250	-	pF	
C_{OSS}	Output Capacitance		-	36	-		
C_{RSS}	Reverse Transfer Capacitance		-	6	-		

Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(ON)}$	Turn-On Delay Time	$V_{DS} = 10V,$ $V_{GS} = 4.5V,$ $R_G = 6\Omega,$ $R_L = 10\Omega,$	-	6.5	-	ns	
T_R	Rise Time		-	14	-		
$T_{D(OFF)}$	Turn-Off Delay Time		-	30	-		
T_F	Fall Time		-	2	-		
Q_G	Total Gate Charge	$V_{DS} = -10V,$ $V_{GS} = 4.5V,$ $I_D = 3.0A$	-	4.7	-	nC	
Q_{GS}	Gate-Source Charge		-	1.9	-		
Q_{GD}	Gate-Drain Charge		-	1.4	-		

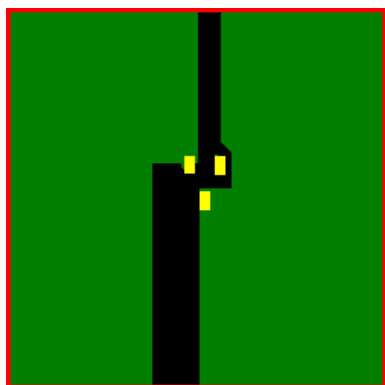


Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V _{SD}	Body Diode Forward Voltage	V _{GS} = 0V, I _D = 3.4A	-	0.8	1.2	V	
I _{SD}	Body Diode Continuous Current		-	-	2.9	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. Device mounted on a glass-epoxy board



FR-4
25.4 × 25.4 mm .
2 Oz Copper

Test Board

3. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
4. Thermal Resistance follow JESD51-3.



Typical Characteristic Curves

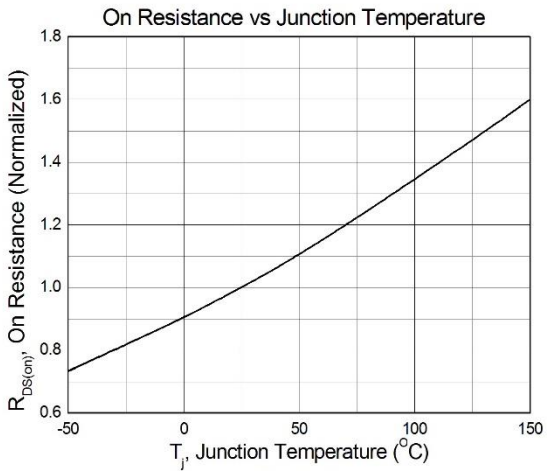


Figure 1

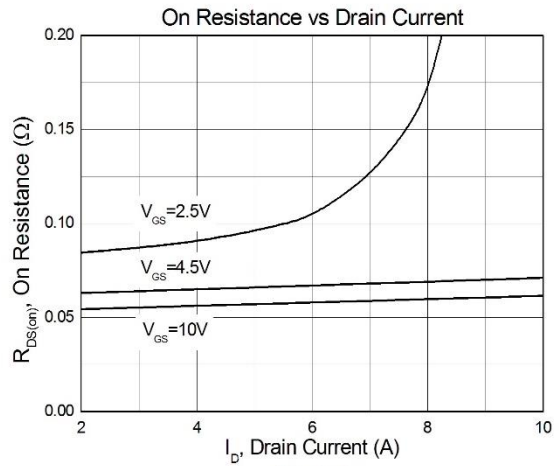


Figure 2

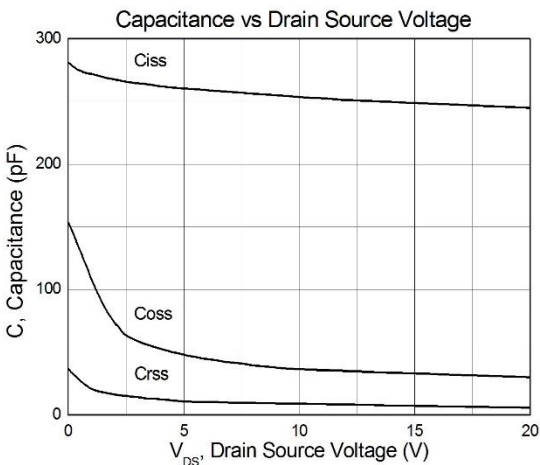


Figure 3

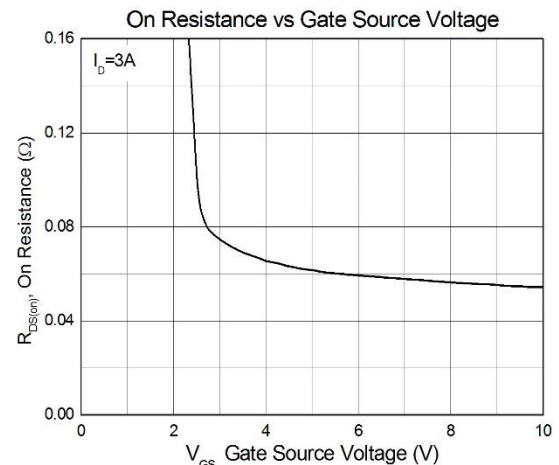


Figure 4

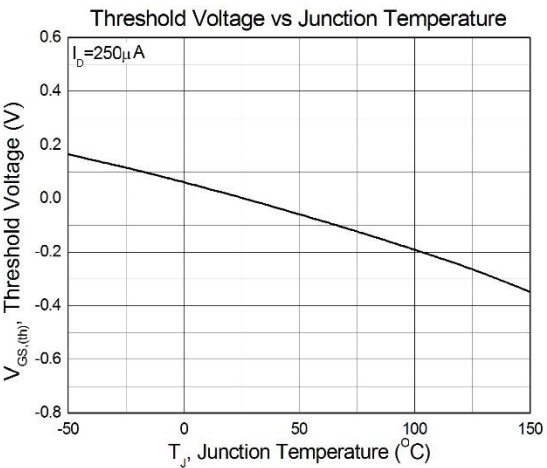


Figure 5

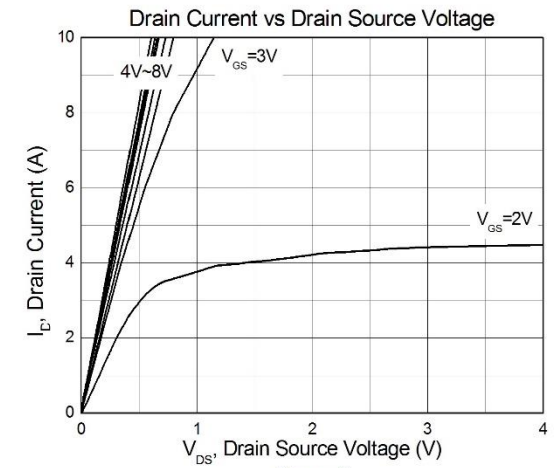
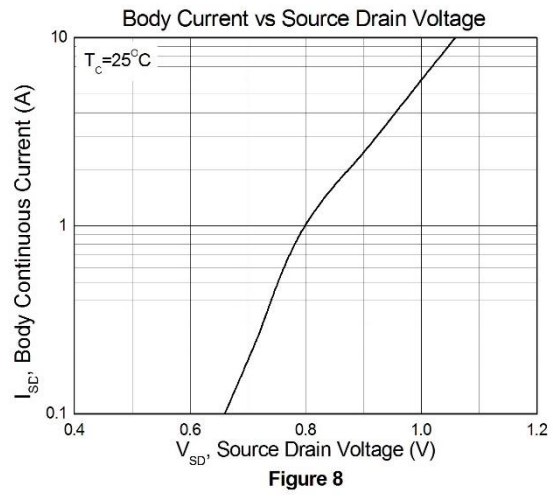
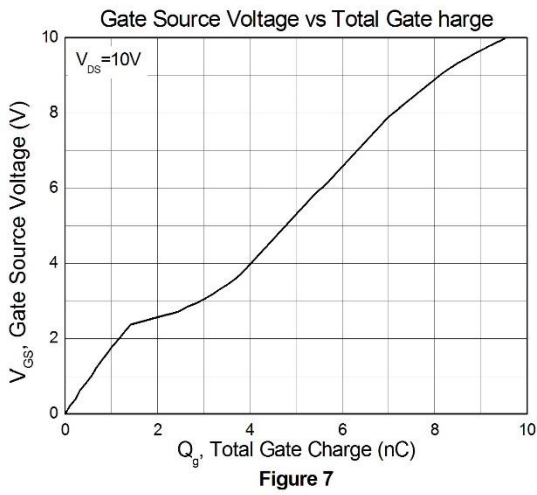


Figure 6





Test Circuits & Waveforms

Figure 12: Gate Charge Test Circuit

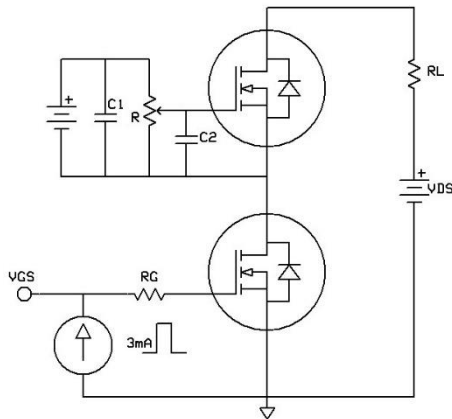


Figure 13: Gate Charge Waveform

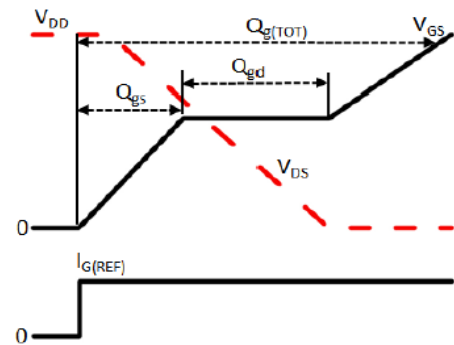


Figure 14: Switching Time Test Circuit

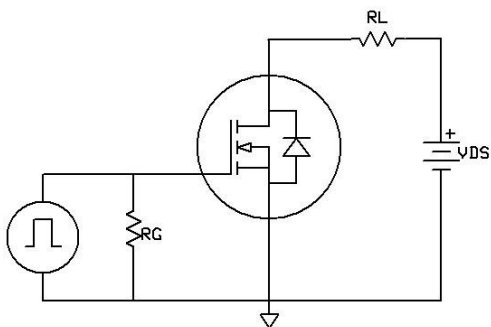
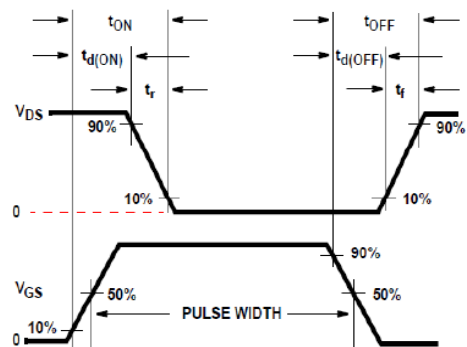
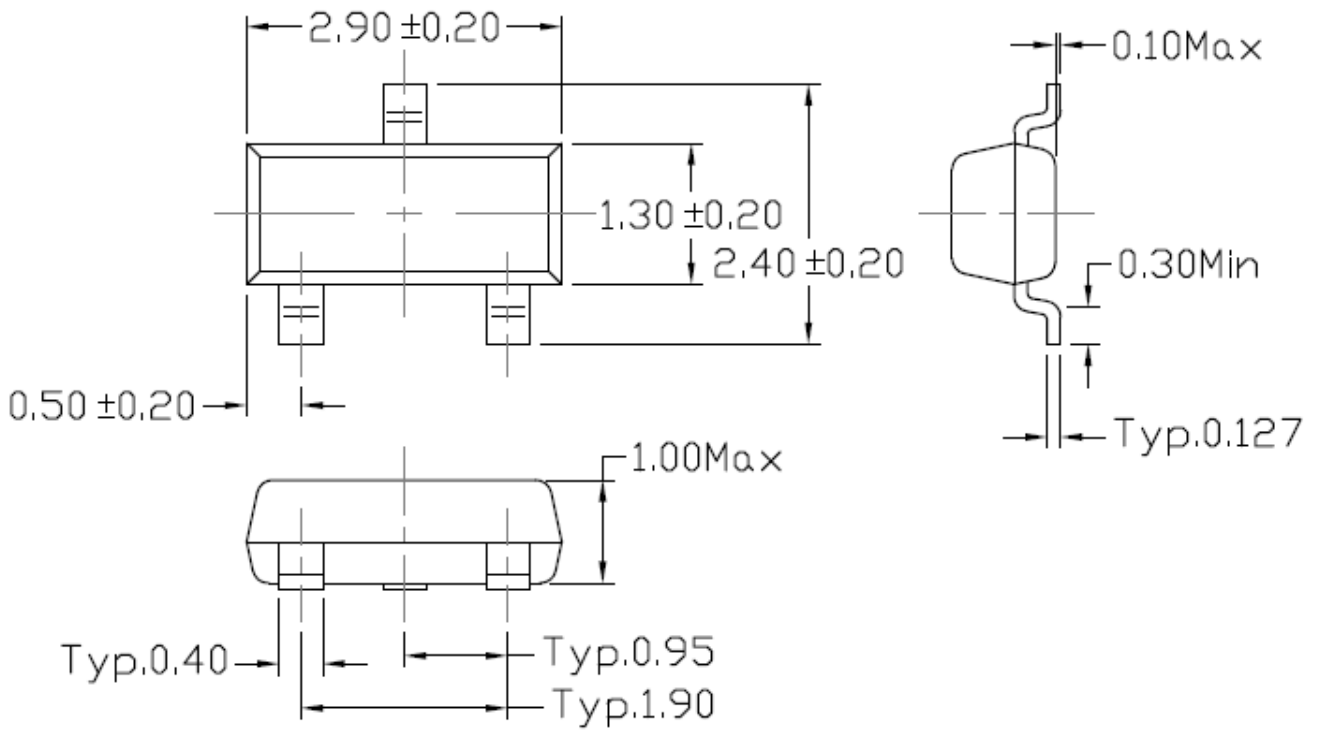


Figure 15: Switching Time Waveform

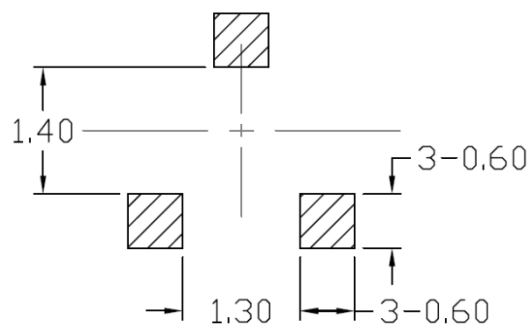




Package Dimension (SOT-23)



Recommended pad layout for surface mount leadform

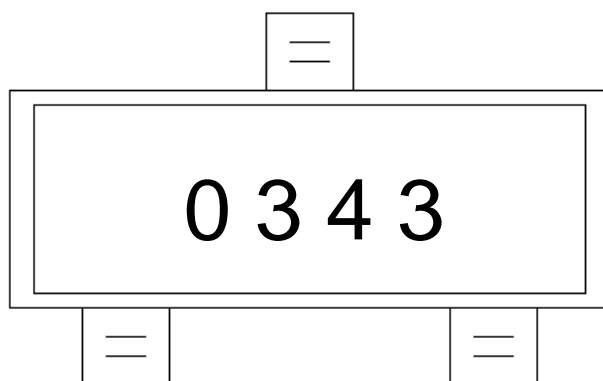




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Marking Information



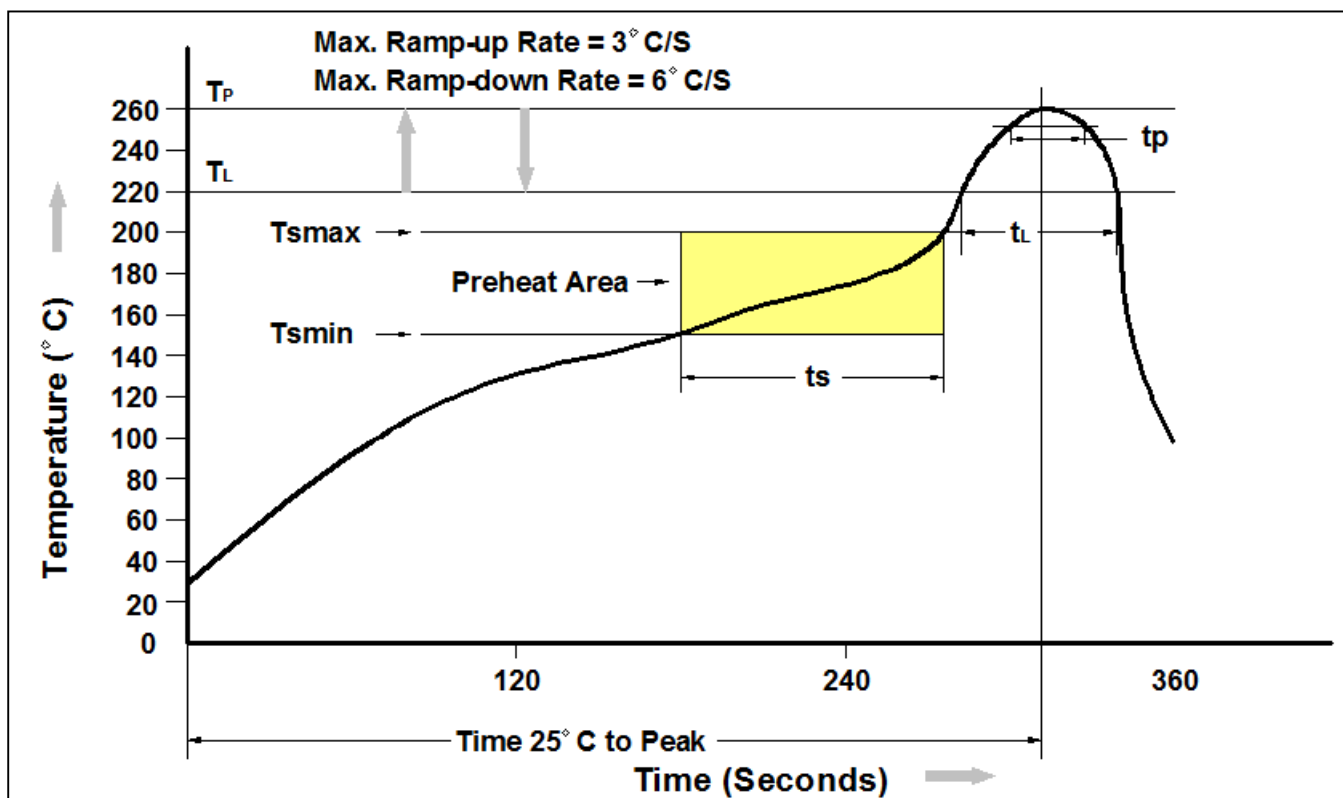
0343: Device Number

Ordering Information

Part Number	Description	Quantity
CTL0343PS-R3	SOT-23 Reel	3000 pcs



Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T _{smin})	150°C
Temperature Max. (T _{smax})	200°C
Time (t _s) from (T _{smin} to T _{smax})	60-120 seconds
Ramp-up Rate (t _L to t _P)	3°C/second max.
Liquidous Temperature (T _L)	217°C
Time (t _L) Maintained Above (T _L)	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (t _P) within 5°C of 260°C	30 seconds
Ramp-down Rate (T _P to T _L)	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.



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